



EXPRESS MAIL LABEL NO. EV016318321US

PATENT APPLICATION  
Docket No: 11675.168.1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of Leonard E. Mess )  
Serial No. 09/501,033 )  
Filed: February 9, 2000 )Art Unit 2858  
For: SYSTEM FOR TESTING A )  
SEMICONDUCTOR DEVICE )  
Examiner: Vinh P. Nguyen )  
Confirmation No.: 3325 )

PROPOSED DRAWING CORRECTIONS

The Assistant Commissioner of Patents  
and Trademarks  
Washington, D. C. 20231  
Sir:

Please add Figs. 10, 11 and 12 as shown in the accompanying sheet. Support for these figures is found in the Application as filed, for example, at p. 11, 4-15, and p. 13, 11. 7-16.

In the event that the Examiner encounters an issue which could be clarified by a telephonic interview, the Examiner is respectfully requested to initiate the same with the undersigned attorney.

DATED this 24<sup>th</sup> day of January, 2002.

Respectfully submitted,

Jesús Juanos Timoneda, Ph.D  
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Amendment "D" and Response / Proposed Drawings  
Serial No. 09/501,033

Title: SYSTEM FOR TESTING A  
SEMICONDUCTOR DEVICE

Applicant: Leonard E. Mess

Serial No.: 09/501,033

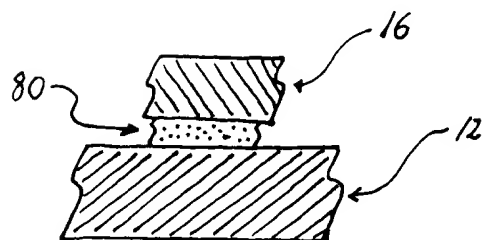


Fig. 10

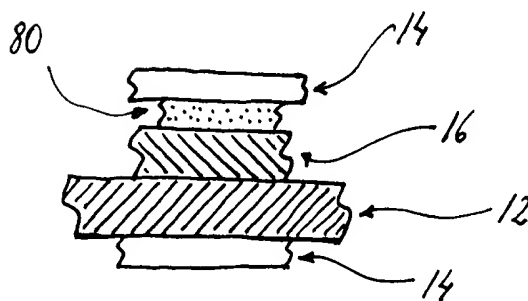


Fig. 11

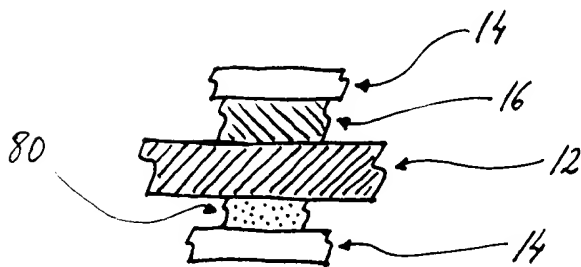


Fig. 12

Title: SYSTEM FOR TESTING A  
SEMICONDUCTOR DEVICE

Applicant: Leonard E. Mess

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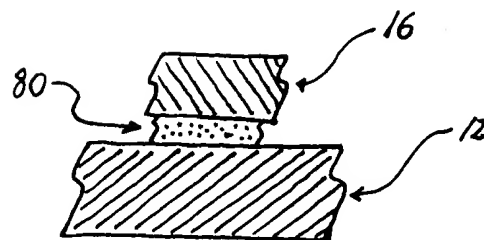


Fig. 10

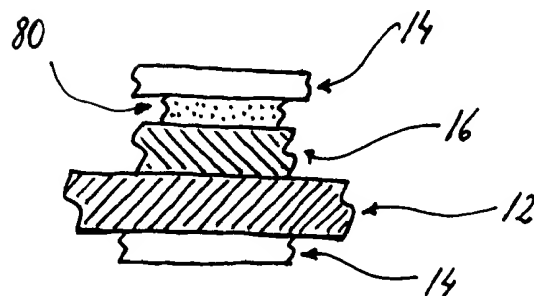


Fig. 11

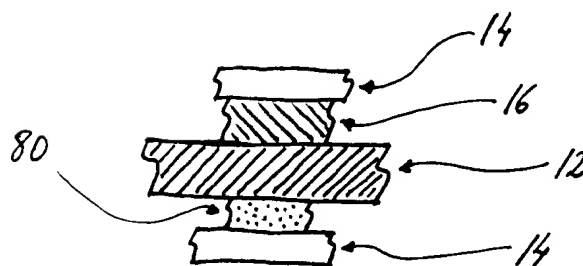


Fig. 12